1. Features

Medium-voltage and Standard-voltage Operation

- 2.7 (V_{CC} = 2.7V to 5.5V)

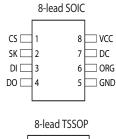
- User-selectable Internal Organization
 1K: 128 x 8 or 64 x 16
- Three-wire Serial Interface
- 2 MHz Clock Rate (5V)
- Self-timed Write Cycle (10 ms max)
- High Reliability
 - Endurance: 1 Million Write Cycles
 - Data Retention: 100 Years
- 8-lead TSSOP and 8-lead JEDEC SOIC Packages

2. Description

The AT93C46 provides 1024 bits of serial electrically erasable programmable read only memory (EEPROM) organized as 64 words of 16 bits each, when the ORG pin is connected to VCC and 128 words of 8 bits each when it is tied to ground. The device is optimized for use in many automotive applications where low power and low voltage operations are essential. The AT93C46 is available in space-saving 8-lead TSSOP and 8-lead JEDEC SOIC packages. The AT93C46 is enabled through the Chip Select pin (CS), and accessed via a 3-wire serial interface consisting of Data Input (DI), Data Output (DO), and Shift Clock (SK). Upon receiving a Read instruction at DI, the address is decoded and the data is clocked out serially on the data output pin DO. The WRITE cycle is completely self-timed and no separate erase cycle is required before write. The Write cycle is only enabled when it is in the Erase/Write Enable state. When CS is brought "high" following the initiation of a write cycle, the DO pin outputs the Ready/Busy status.

Table 2-1.	Pin Configuration
	Fin Connyuration

	<u> </u>
Pin Name	Function
CS	Chip Select
SK	Serial Data Clock
DI	Serial Data Input
DO	Serial Data Output
GND	Ground
VCC	Power Supply
ORG	Internal Organization







Three-wire Automotive Temperature Serial EEPROMs

1K (128 x 8 or 64 x 16)

AT93C46

Rev. 5125C-SEEPR-11/07



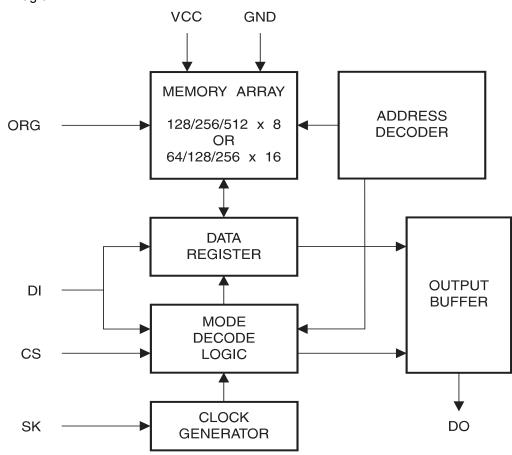


3. Absolute Maximum Ratings*

Operating Temperature55°C to +125°C	*N
Storage Temperature65°C to +150°C	
Voltage on Any Pin with Respect to Ground–1.0V to +7.0V	
Maximum Operating Voltage	
DC Output Current 5.0 mA	

NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

Figure 3-1. Block Diagram



Note: When the ORG pin is connected to VCC, the "x 16" organization is selected. When it is connected to ground, the "x 8" organization is selected. If the ORG pin is left unconnected and the application does not load the input beyond the capability of the internal 1 Meg ohm pullup, then the "x 16" organization is selected.

For the AT93C46, if "x 16" organization is the mode of choice and Pin 6 (ORG) is left unconnected, Atmel recommends using the AT93C46A device. For more details, see the AT93C46A datasheet.

Table 3-1.Pin Capacitance⁽¹⁾

Applicable over recommended operating range from $T_A = 25^{\circ}C$, f = 1.0 MHz, $V_{CC} = +5.0V$ (unless otherwise noted)

Symbol	Test Conditions	Мах	Units	Conditions
C _{OUT}	Output Capacitance (DO)	5	pF	V _{OUT} = 0V
C _{IN}	Input Capacitance (CS, SK, DI)	5	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

Table 3-2.DC Characteristics

Applicable over recommended operating range from: $T_A = -40^{\circ}C$ to $+125^{\circ}C$, $V_{CC} = +2.7V$ to +5.5V (unless otherwise noted)

Symbol	Parameter	Test Condition		Min	Тур	Max	Unit
V _{CC1}	Supply Voltage			2.7		5.5	V
V _{CC2}	Supply Voltage			4.5		5.5	V
			READ at 1.0 MHz		0.5	2.0	mA
I _{CC}	Supply Current	$V_{\rm CC} = 5.0 V$	WRITE at 1.0 MHz		0.5	2.0	mA
I _{SB1}	Standby Current	V _{CC} = 2.7V	CS = 0V		6.0	10.0	μA
I _{SB2}	Standby Current	V _{CC} = 5.0V	CS = 0V		10.0	15.0	μA
I _{IL}	Input Leakage	$V_{IN} = 0V$ to V_{CC}	$V_{IN} = 0V$ to V_{CC}		0.1	1.0	μA
I _{OL}	Output Leakage	$V_{IN} = 0V$ to V_{CC}			0.1	1.0	μA
V _{IL1} ⁽¹⁾	Input Low Voltage			-0.6		0.8	
V _{IH1} ⁽¹⁾	Input High Voltage	$2.7V \le V_{CC} \le 5.5V$		2.0		V _{CC} + 1	V
V _{OL1}	Output Low Voltage		I _{OL} = 2.1 mA			0.4	V
V _{OH1}	Output High Voltage	$2.7V \le V_{CC} \le 5.5V$	I _{OH} = -0.4 mA	2.4			V

Note: 1. V_{IL} min and V_{IH} max are reference only and are not tested.





Table 3-3.AC Characteristics

Applicable over recommended operating range from $T_A = -40^{\circ}C$ to + 125°C, V_{CC} = As Specified, CL = 1 TTL Gate and 100 pF (unless otherwise noted)

Symbol	Parameter	Test Condition		Min	Тур	Max	Units
f _{SK}	SK Clock Frequency	$\begin{array}{c} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \end{array}$		0 0		2 1	MHz
t _{sкн}	SK High Time	$\begin{array}{c} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \end{array}$		250 250			ns
t _{SKL}	SK Low Time	$\begin{array}{c} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \end{array}$		250 250			ns
t _{CS}	Minimum CS Low Time	$\begin{array}{l} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \end{array}$		250 250			ns
t _{css}	CS Setup Time	Relative to SK	$\begin{array}{c} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \\ \end{array} \label{eq:VCC}$	50 50			ns
t _{DIS}	DI Setup Time	Relative to SK	$\begin{array}{l} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \end{array}$	100 100			ns
t _{CSH}	CS Hold Time	Relative to SK		0			ns
t _{DIH}	DI Hold Time	Relative to SK	$\begin{array}{l} 4.5V \leq V_{CC} \ \leq 5.5V \\ 2.7V \leq V_{CC} \ \leq 5.5V \end{array}$	100 100			ns
t _{PD1}	Output Delay to '1'	AC Test	$\begin{array}{l} 4.5 V \leq V_{CC} \\ 2.7 V \leq V_{CC} \\ \leq 5.5 V \end{array}$			250 500	ns
t _{PD0}	Output Delay to '0'	AC Test	$\begin{array}{l} 4.5V \leq V_{CC} \\ 2.7V \leq V_{CC} \\ \leq 5.5V \end{array}$			250 500	ns
t _{SV}	CS to Status Valid	AC Test	$\begin{array}{l} 4.5 V \leq V_{CC} \\ 2.7 V \leq V_{CC} \\ \leq 5.5 V \end{array}$			250 250	ns
t _{DF}	CS to DO in High Impedance	AC Test CS = V _{IL}	$\begin{array}{c} 4.5 V \leq V_{CC} \\ 2.7 V \leq V_{CC} \\ \leq 5.5 V \end{array}$			100 150	ns
t _{WP}	Write Cycle Time		$2.7V \leq V_{CC} \ \leq 5.5V$		3	10	ms
Endurance ⁽¹⁾	5.0V, 25°C			1M			Write Cycles

Note: 1. This parameter is ensured by characterization only.

4

		Ор	Add	ress	Data		
Instruction	SB	Code	x 8	x 16	x 8	x 16	Comments
READ	1	10	A ₆ - A ₀	A ₅ - A ₀			Reads data stored in memory, at specified address
EWEN	1	00	11XXXXX	11XXXX			Write enable must precede all programming modes
ERASE	1	11	A ₆ - A ₀	A ₅ - A ₀			Erase memory location $A_n - A_0$
WRITE	1	01	A ₆ - A ₀	A ₅ - A ₀	D ₇ - D ₀	D ₁₅ - D ₀	Writes memory location $A_n - A_0$
ERAL	1	00	10XXXXX	10XXXX			Erases all memory locations. Valid only at V_{CC} = 4.5V to 5.5V
WRAL	1	00	01XXXXX	01XXXX	D ₇ - D ₀	D ₁₅ - D ₀	Writes all memory locations. Valid only at V_{CC} = 4.5V to 5.5V
EWDS	1	00	00XXXXX	00XXXX			Disables all programming instructions

Table 3-4. Instruction Set for the AT93C46

Note ddress field represent don't care values and must be clocked.

Table 3-5. Instruction Set for the AT93C56⁽¹⁾ and AT93C66⁽²⁾

		Ор	Address		Address Data		ata	
Instruction	SB	Code	x 8	x 16	x 8	x 16	Comments	
READ	1	10	A ₈ - A ₀	A ₇ - A ₀			Reads data stored in memory, at specified address	
EWEN	1	00	11XXXXXXX	11XXXXXX			Write enable must precede all programming modes	
ERASE	1	11	A ₈ - A ₀	A ₇ - A ₀			Erase memory location A _n - A ₀	
WRITE	1	01	A ₈ - A ₀	A ₇ - A ₀	D ₇ - D ₀	D ₁₅ - D ₀	Writes memory location A _n - A ₀	
ERAL	1	00	10XXXXXXX	10XXXXXX			Erases all memory locations. Valid only at V_{CC} = 4.5V to 5.5V	
WRAL	1	00	01XXXXXXX	01XXXXXX	D ₇ - D ₀	D ₁₅ - D ₀	Writes all memory locations. Valid only at V_{CC} = 5.0V ±10% and Disable Register cleared	
EWDS	1	00	00XXXXXXX	00XXXXXX			Disables all programming instructions	

Note: 1. This device is not recommended for new designs. Please refer to AT93C56A.

2. This device is not recommended for new designs. Please refer to AT93C66A.

3. The Xs in the address field represent don't care values and must be clocked.

Functional Description 4.

The AT93C46/56/66 is accessed via a simple and versatile 3-wire serial communication interface. Device operation is controlled by seven instructions issued by the host processor. A valid instruction starts with a rising edge of CS and consists of a Start Bit (logic "1") followed by the appropriate Op Code and the desired memory Address location.

READ (READ): The Read (READ) instruction contains the address code for the memory location to be read. After the instruction and address are decoded, data from the selected memory





location is available at the serial output pin DO. Output data changes are synchronized with the rising edges of serial clock SK. It should be noted that a dummy bit (logic "0") precedes the 8- or 16-bit data output string.

ERASE/WRITE (EWEN): To assure data integrity, the part automatically goes into the Erase/Write Disable (EWDS) state when power is first applied. An Erase/Write Enable (EWEN) instruction must be executed first before any programming instructions can be carried out. Please note that once in the EWEN state, programming remains enabled until an EWDS instruction is executed or V_{CC} power is removed from the part.

ERASE (ERASE): The Erase (ERASE) instruction programs all bits in the specified memory location to the logical "1" state. The self-timed erase cycle starts once the ERASE instruction and address are decoded. The DO pin outputs the Ready/Busy status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). A logic "1" at pin DO indicates that the selected memory location has been erased, and the part is ready for another instruction.

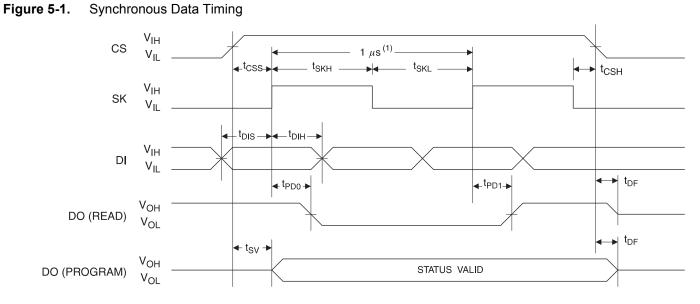
WRITE (WRITE): The Write (WRITE) instruction contains the 8 or 16 bits of data to be written into the specified memory location. The self-timed programming cycle, t_{WP} , starts after the last bit of data is received at serial data input pin DI. The DO pin outputs the Ready/Busy status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). A logic "0" at DO indicates that programming is still in progress. A logic "1" indicates that the memory location at the specified address has been written with the data pattern contained in the instruction and the part is ready for further instructions. A Ready/Busy status cannot be obtained if the CS is brought high after the end of the self-timed programming cycle, t_{WP} .

ERASE ALL (ERAL): The Erase All (ERAL) instruction programs every bit in the memory array to the logic "1" state and is primarily used for testing purposes. The DO pin outputs the Ready/Busy status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). The ERAL instruction is valid only at V_{CC} = 5.0V ± 10%.

WRITE ALL (WRAL): The Write All (WRAL) instruction programs all memory locations with the data patterns specified in the instruction. The DO pin outputs the Ready/Busy status of the part if CS is brought high after being kept low for a minimum of 250 ns (t_{CS}). The WRAL instruction is valid only at V_{CC} = 5.0V ± 10%.

ERASE/WRITE DISABLE (EWDS): To protect against accidental data disturb, the Erase/Write Disable (EWDS) instruction disables all programming modes and should be executed after all programming operations. The operation of the Read instruction is independent of both the EWEN and EWDS instructions and can be executed at any time.

5. Timing Diagrams



Note: 1. This is the minimum SK period.

 Table 5-1.
 Organization Key for Timing Diagrams

	AT93C46 (1K)		AT93C56 (2K) ⁽¹⁾		AT93C66 (4K) ⁽²⁾	
I/O	x 8	x 16	x 8	x 16	x 8	x 16
A _N	A ₆	A ₅	A ₈ ⁽³⁾	A ₇ ⁽⁴⁾	A ₈	A ₇
D _N	D ₇	D ₁₅	D ₇	D ₁₅	D ₇	D ₁₅

Notes: 1. This device is not recommended for new designs. Please refer to AT93C56A.

2. This device is not recommended for new designs. Please refer to AT93C66A.

- 3. A_8 is a *don't care* value, but the extra clock is required.
- 4. A_7 is a *don't care* value, but the extra clock is required.

Figure 5-2. READ Timing

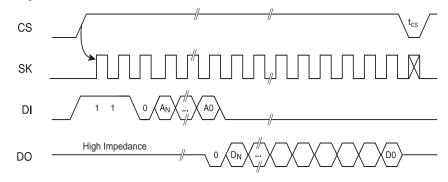






Figure 5-3. EWEN Timing

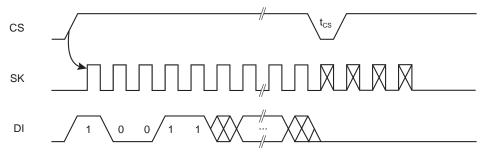


Figure 5-4. EWDS Timing

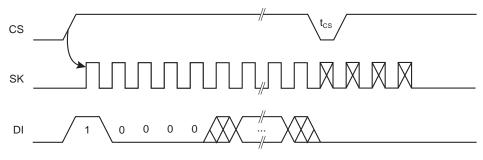


Figure 5-5. WRITE Timing

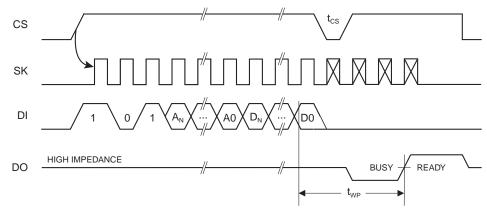
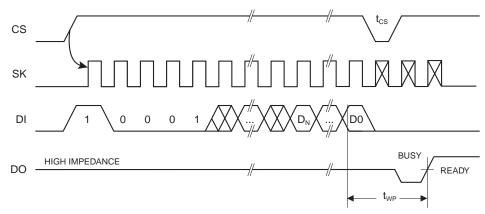


Figure 5-6. WRAL Timing⁽¹⁾



8

Note: 1. Valid only at V_{CC} = 4.5V to 5.5V.



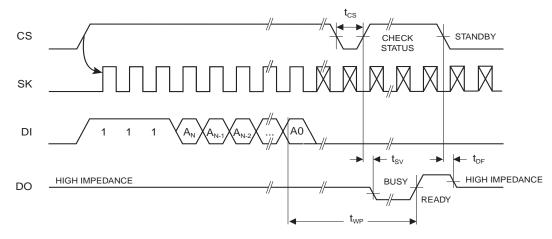
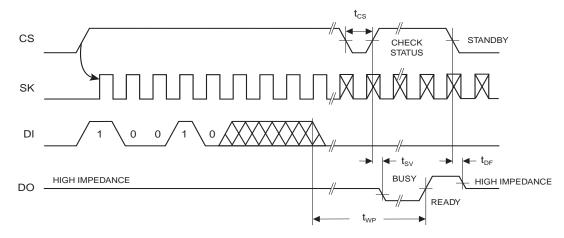


Figure 5-8. ERAL Timing⁽¹⁾



Note: 1. Valid only at V_{CC} = 4.5V to 5.5V.





6. AT93C46 Ordering Information

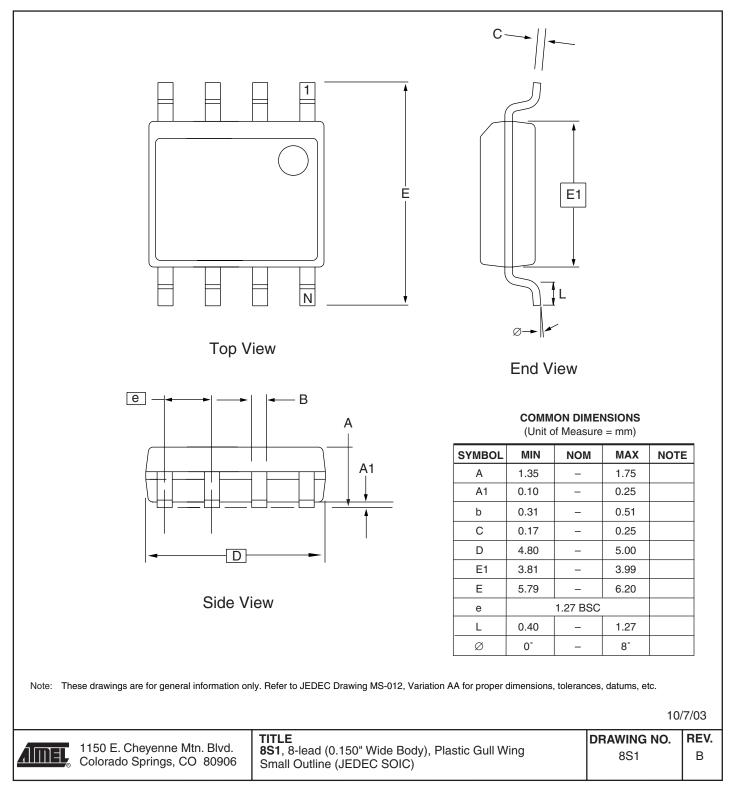
Ordering Code	Package	Operation Range
AT93C46-10SQ-2.7	8S1	Lead-Free/Halogen Free
	8A2	Automotive Temperature
AT93C46-10TQ-2.7	OAZ	(–40°C to 125°C)

	Package Type				
8S1	8S1 8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)				
8A2	8A2 8-lead, 4.4 mm Body, Plastic Thin Shrink Small Outline Package (TSSOP)				
	Options				
-2.7	Low Voltage (2.7V to 5.5V)				

10 AT93C46

Packaging Information

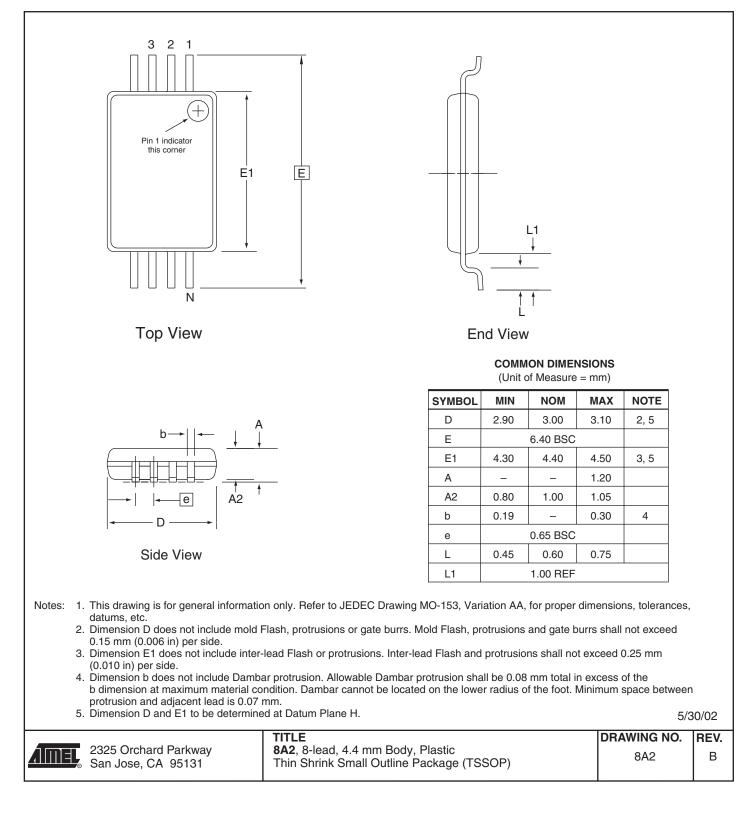
8S1 – JEDEC SOIC







8A2 - TSSOP



Revision History

Doc. Rev.	Date	Comments
5125C	11/2007	Updated to new template Changed max value of $V_{il1},V_{ih1},andt_{DF}$
5125B	1/2007	Implemented revision history Removed PDIP package offering Removed Pb'd parts





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